

February 2012
UniFET-IITM

# FDP8N50NZF / FDPF8N50NZF N-Channel MOSFET 500V, 7A, $1\Omega$

#### **Features**

- $P_{DS(on)} = 0.85\Omega$  ( Typ.) @  $V_{GS} = 10V$ ,  $I_D = 3.25A$
- Low Gate Charge (Typ. 14nC)
- Low C<sub>ss</sub> (Typ. 5pF)
- Fast Switching
- 100% Avalanche Tested
- · Improve dv/dt Capability
- · ESD Improved Capability
- RoHS Compliant

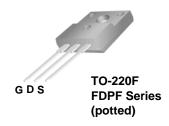


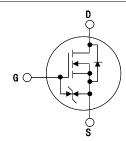
# **Description**

This N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.







# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol		Parameter		FDP8N50NZF	FDPF8N50NZF	Units
$V_{DSS}$	Drain to Source Voltage	Orain to Source Voltage			500	V
$V_{GSS}$	Gate to Source Voltage	Gate to Source Voltage			±25	V
	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		7	7*	^
ID	Drain Current	-Continuous (T <sub>C</sub> = 100°C)		4.2	4.2*	A
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	28	28*	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy		(Note 2)	93		mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	7		Α
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	13		mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20		V/ns
D	Dawer Discipation	$(T_C = 25^{\circ}C)$		130	40	W
$P_{D}$	Power Dissipation	- Derate above 25°C		1	0.32	W/oC
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 1	to +150	°С	
T <sub>L</sub>	Maximum Lead Temperature for 1/8" from Case for 5 Seconds	Maximum Lead Temperature for Soldering Purpose,			300	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

#### **Thermal Characteristics**

Symbol	Parameter	FDP8N50NZF	FDPF8N50NZF	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.96	3.1	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP8N50NZF	FDP8N50NZF	TO-220	-	-	50
FDPF8N50NF	FDPF8N50NZF	TO-220F	=	=	50

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter Test Conditions		Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250\mu A$ , $V_{GS} = 0V$ , $T_C = 25^{\circ}C$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.5	-	V/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 500V, V_{GS} = 0V$	-	-	10	
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 400V, T_C = 125^{\circ}C$	-	-	100	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$	-	-	±10	μΑ

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250\mu A$	3.0	-	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 3.5A$	-	0.85	1	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20V, I_D = 3.5A$ (Note 4)	-	6.3	i	S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05V V 0V	-	565	735	pF
Coss	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz	-	80	105	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112	-	5	8	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	14	18	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 400 V, I_{D} = 7 A$	-	4	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V (Note 4,	5) -	6	-	nC

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	17	45	ns	
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 250V$ , $I_D = 7A$	-	34	80	ns	
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25\Omega$ , $V_{GS} = 10V$	-	43	95	ns	
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)	-	27	60	ns	

# **Drain-Source Diode Characteristics**

Is	Maximum Continuous Drain to Source Diode Forward Current		-	-	7	Α	
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	28	Α	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V$ , $I_{SD} = 7A$		-	-	1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 7A		-	80	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	(Note 4)	-	0.3	-	μС

- Notes:

  1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 3.8mH, I  $_{AS}$  = 7A, V  $_{DD}$  = 50V, R  $_{G}$  = 25  $\!\Omega$  , Starting T  $_{J}$  = 25  $^{\circ}C$
- 3. I  $_{SD} \le$  7A, di/dt  $\le$  200A/ $\mu$ s, V  $_{DD} \le$  BV  $_{DSS}$ , Starting T  $_{J}$  = 25°C
- 4. Pulse Test: Pulse width  $\leq 300 \mu s, \, \text{Duty Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

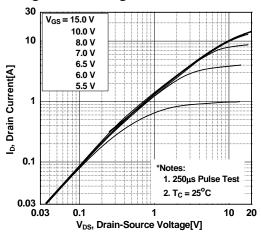


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

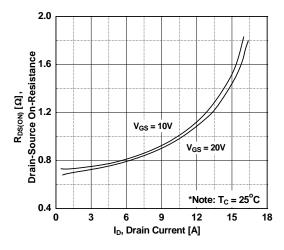


Figure 5. Capacitance Characteristics

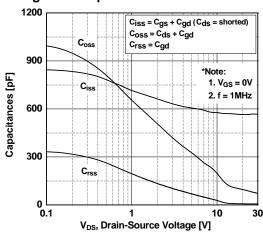


Figure 2. Transfer Characteristics

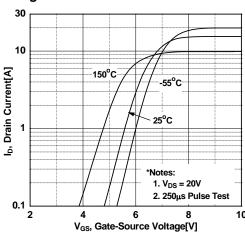


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

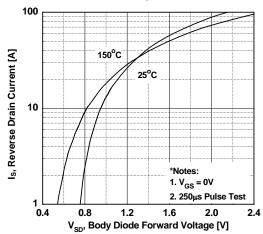
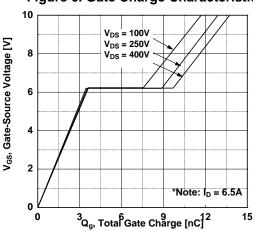


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics (Continued)**

Figure 7. Breakdown Voltage Variation vs. Temperature

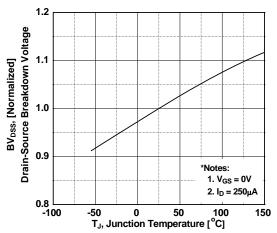


Figure 8. Maximum Safe Operating Area - FDPF8N50NZF

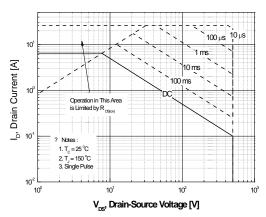


Figure 9. Maximum Drain Current vs. Case Temperature

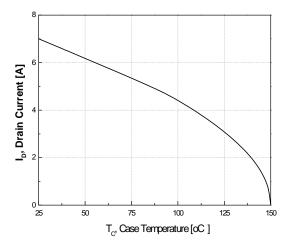
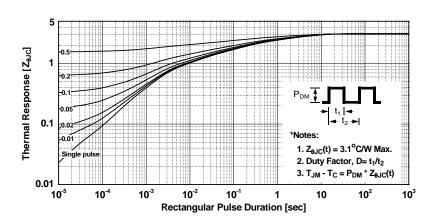
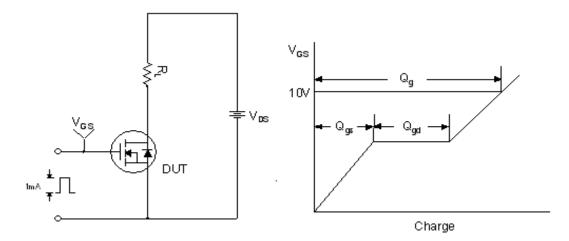


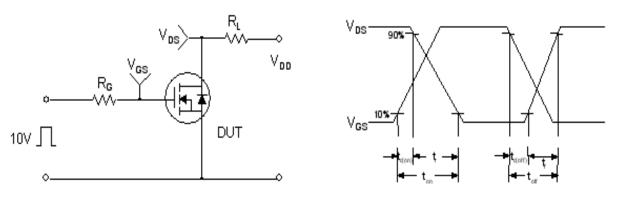
Figure 11. Transient Thermal Response Curve -FDPF8N50NZF



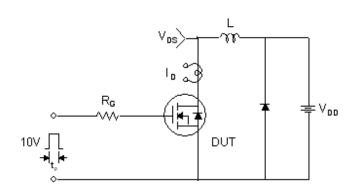
# **Gate Charge Test Circuit & Waveform**

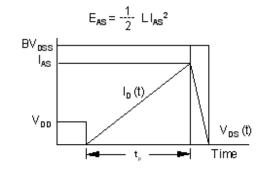


## **Resistive Switching Test Circuit & Waveforms**

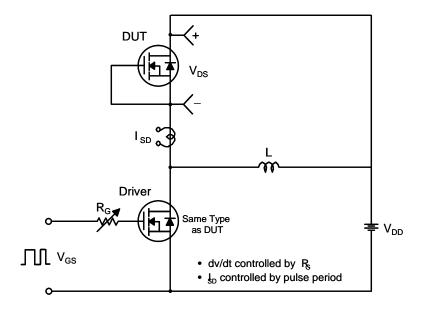


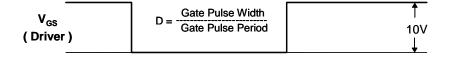
**Unclamped Inductive Switching Test Circuit & Waveforms** 

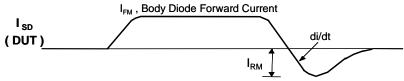




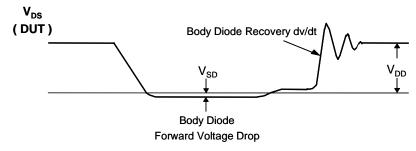
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms





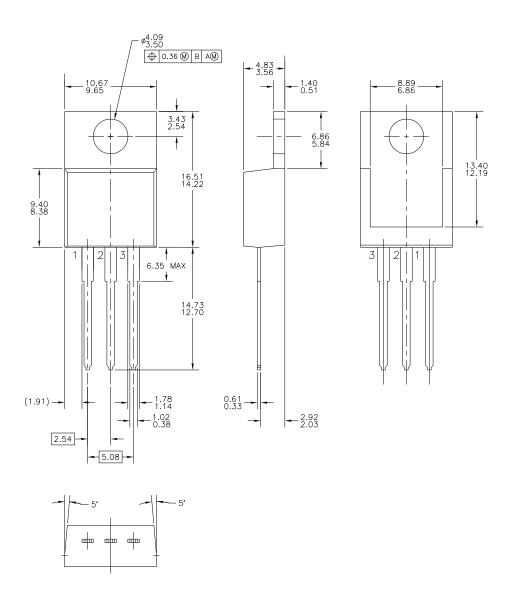


**Body Diode Reverse Current** 



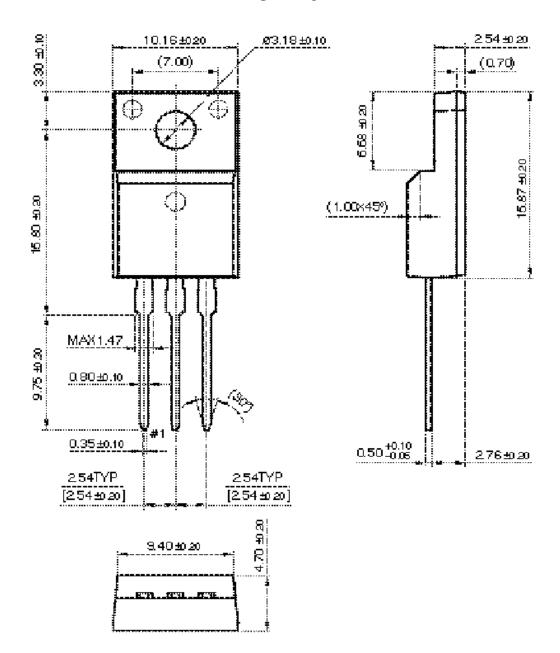
# **Mechanical Dimensions**

# TO-220



# **Package Dimensions**

# TO-220F



\* Front/Back Side Isolation Voltage : AC 2500V

Dimensions in Millimeters





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